

Description

The VSM35N03 uses advanced trench technology and design to provide excellent $R_{DS(ON)}$ with low gate charge. It can be used in a wide variety of applications.

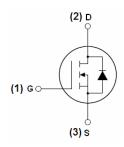
General Features

- $V_{DS} = 30V, I_D = 35A$ $R_{DS(ON)} < 15m\Omega @ V_{GS} = 10V$
- High density cell design for ultra low Rdson
- Fully characterized Avalanche voltage and current
- Good stability and uniformity with high E_{AS}
- Excellent package for good heat dissipation
- Special process technology for high ESD capability

Application

- Power switching application
- Hard switched and high frequency circuits
- Uninterruptible Power Supply





TO-252

Schematic Diagram

Package Marking and Ordering Information

| Device Marking | Device | Device Package | Reel Size | Tape width | Quantity |
|----------------|----------|----------------|-----------|------------|----------|
| VSM35N03-T2 | VSM35N03 | TO-252 | - | - | - |

Absolute Maximum Ratings (T_c=25℃unless otherwise noted)

| Parameter | Symbol | Limit | Unit | |
|--|-----------------------|------------|--------------|--|
| Drain-Source Voltage | V _{DS} | 30 | V | |
| Gate-Source Voltage | Vgs | ±20 | V | |
| Drain Current-Continuous | I _D | 35 | А | |
| Drain Current-Continuous(T _C =100 °C) | I _D (100℃) | 35 | А | |
| Pulsed Drain Current | I _{DM} | 24.8 | А | |
| Maximum Power Dissipation | P _D | 45 | W | |
| Derating factor | | 0.36 | W/°C | |
| Single pulse avalanche energy (Note 5) | E _{AS} | 225 | mJ | |
| Operating Junction and Storage Temperature Range | T_{J}, T_{STG} | -55 To 150 | $^{\circ}$ C | |



Shenzhen VSEEI Semiconductor Co., Ltd

Thermal Characteristic

| Thermal Resistance, Junction-to-Case (Note 2) | R _{eJC} | 2.8 | °C/W |
|---|------------------|-----|------|
|---|------------------|-----|------|

Electrical Characteristics (T_c=25°Cunless otherwise noted)

| Parameter | Symbol | Condition | Min | Тур | Max | Unit |
|------------------------------------|---------------------|--|-----|------|------|------|
| Off Characteristics | • | | • | | | |
| Drain-Source Breakdown Voltage | BV _{DSS} | V _{GS} =0V I _D =250μA | 30 | 33 | - | V |
| Zero Gate Voltage Drain Current | I _{DSS} | V _{DS} =30V,V _{GS} =0V | - | - | 1 | μΑ |
| Gate-Body Leakage Current | I _{GSS} | V _{GS} =±20V,V _{DS} =0V | - | - | ±100 | nA |
| On Characteristics (Note 3) | · | | | | | |
| Gate Threshold Voltage | V _{GS(th)} | $V_{DS}=V_{GS}$, $I_{D}=250\mu A$ | 1 | 1.5 | 2.5 | V |
| Drain-Source On-State Resistance | R _{DS(ON)} | V _{GS} =10V, I _D =20A | - | 10 | 14 | mΩ |
| Forward Transconductance | g Fs | V _{DS} =5V,I _D =20A | - | 26 | - | S |
| Dynamic Characteristics (Note4) | | | | | | |
| Input Capacitance | C _{lss} | ., .=.,, | - | 938 | - | PF |
| Output Capacitance | Coss | V_{DS} =15V, V_{GS} =0V, | - | 142 | - | PF |
| Reverse Transfer Capacitance | C _{rss} | F=1.0MHz | - | 99 | - | PF |
| Switching Characteristics (Note 4) | • | | • | | | |
| Turn-on Delay Time | t _{d(on)} | | - | 10 | - | nS |
| Turn-on Rise Time | t _r | V _{DD} =15V,I _D =20A | - | 8 | - | nS |
| Turn-Off Delay Time | t _{d(off)} | V_{GS} =10V, R_{GEN} =1.8 Ω | - | 30 | - | nS |
| Turn-Off Fall Time | t _f | | - | 5 | - | nS |
| Total Gate Charge | Qg | \/ -4F\/ -20A | - | 22 | - | nC |
| Gate-Source Charge | Q _{gs} | $V_{DS}=15V,I_{D}=20A,$ $V_{GS}=10V$ | - | 4.2 | - | nC |
| Gate-Drain Charge | Q _{gd} | V _{GS} -10V | - | 4.8 | - | nC |
| Drain-Source Diode Characteristics | · | | | | | |
| Diode Forward Voltage (Note 3) | V _{SD} | V _{GS} =0V,I _S =25A | - | 0.85 | 1.2 | V |
| Diode Forward Current (Note 2) | Is | | - | - | 35 | Α |
| Reverse Recovery Time | t _{rr} | TJ = 25°C, IF = 20A | - | 20 | - | nS |
| Reverse Recovery Charge | Qrr | di/dt = 100A/µs ^(Note3) | - | 23 | - | nC |
| Forward Turn-On Time | t _{on} | Intrinsic turn-on time is negligible (turn-on is dominated by LS+LD) | | | | |

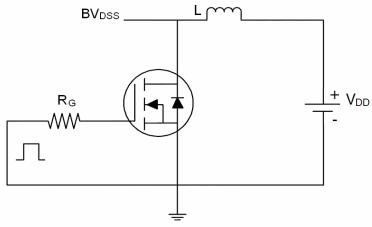
Notes:

- 1. Repetitive Rating: Pulse width limited by maximum junction temperature.
- 2. Surface Mounted on FR4 Board, t ≤ 10 sec.
- **3.** Pulse Test: Pulse Width ≤ 300µs, Duty Cycle ≤ 2%.
- 4. Guaranteed by design, not subject to production
- **5.** EAS condition: Tj=25 $^{\circ}$ C, V_{DD}=15V,V_G=10V,L=0.5mH, Rg=25 Ω

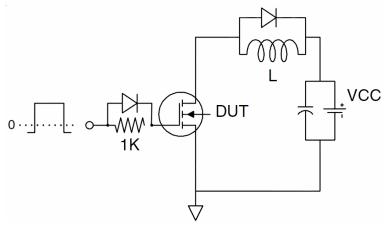


Test circuit

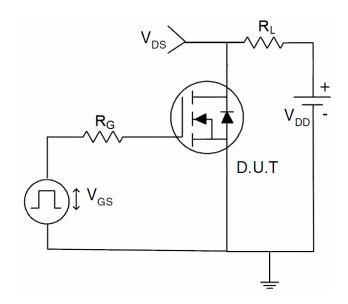
1) E_{AS} test Circuits



2) Gate charge test Circuit:

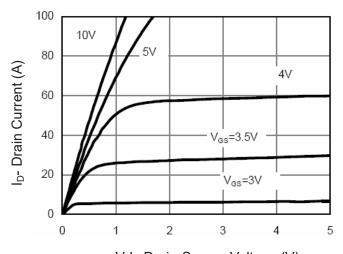


3) Switch Time Test Circuit:





Typical Electrical and Thermal Characteristics (Curves)



Vds Drain-Source Voltage (V)

Figure 1 Output Characteristics

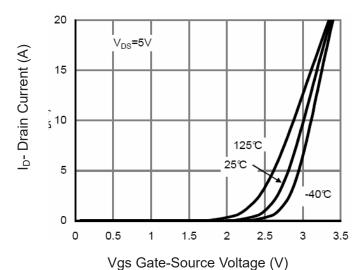
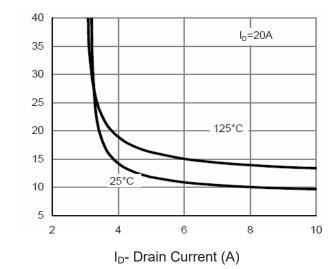


Figure 2 Transfer Characteristics



Rdson On-Resistance Normalized

Figure 3 Rdson- Drain Current

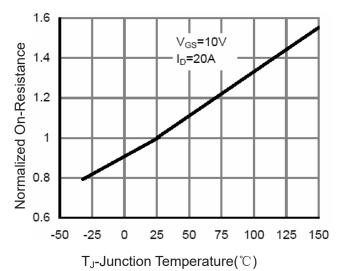


Figure 4 Rdson-JunctionTemperature

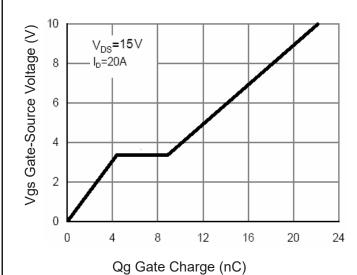


Figure 5 Gate Charge

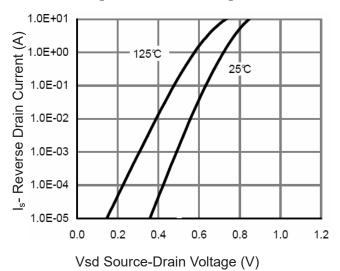


Figure 6 Source- Drain Diode Forward



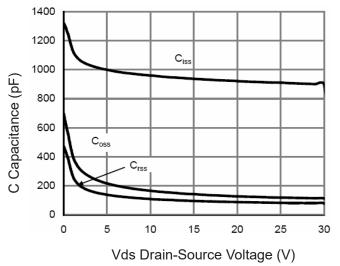


Figure 7 Capacitance vs Vds

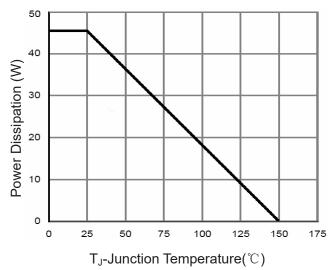


Figure 9 Power De-rating

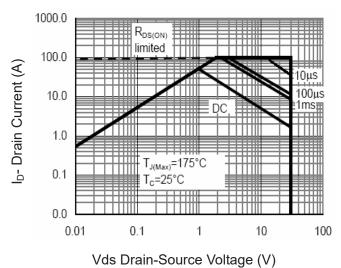


Figure 8 Safe Operation Area

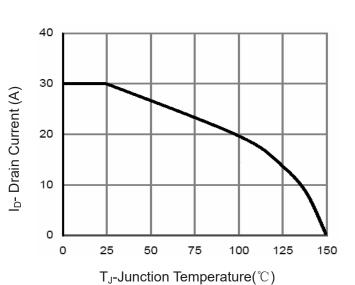


Figure 10 Current De-rating

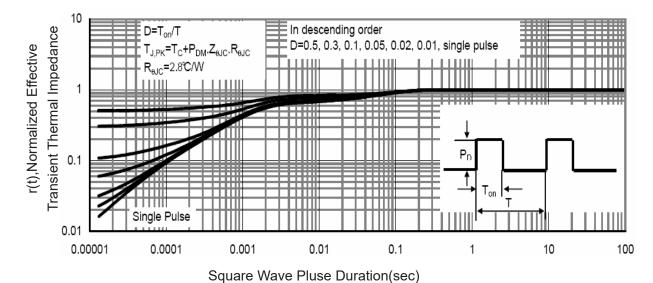


Figure 11 Normalized Maximum Transient Thermal Impedance